



STW29NK50ZD

N-CHANNEL 500 V - 0.11Ω - 29A TO-247
Fast Diode SuperMESH™ MOSFET

PRODUCT PREVIEW

Table 1: General Features

TYPE	V _{DSS}	R _{DS(on)}	I _D	P _W
STW29NK50ZD	500 V	< 0.15 Ω	29 A	350 W

- TYPICAL R_{DS(on)} = 0.11 Ω
- HIGH dv/dt CAPABILITY
- 100% AVALANCHE TESTED
- GATE CHARGE MINIMIZED
- LOW INTRINSIC CAPACITANCES
- VERY GOOD MANUFACTURING REPEATIBILITY
- FAST INTERNAL RECOVERY TIME

DESCRIPTION

The Fast SuperMesh™ series associates all advantages of reduced on-resistance, zener gate protection and very good dv/dt capability with a Fast body-drain recovery diode. Such series complements the "FDmesh™" Advanced Technology.

APPLICATIONS

- HID BALLAST
- ZVS PHASE-SHIFT FULL BRIDGE

Figure 1: Package

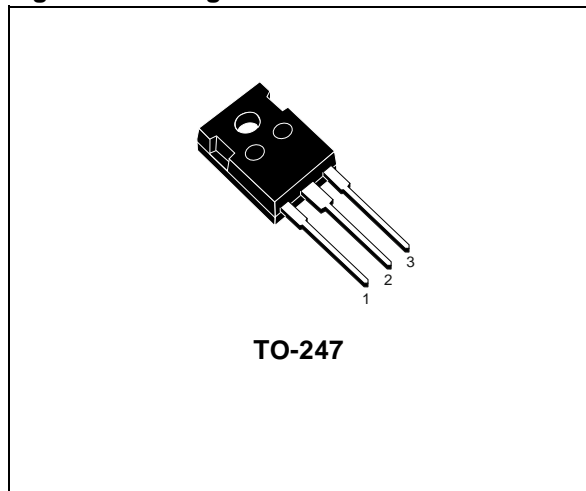


Figure 2: Internal Schematic Diagram

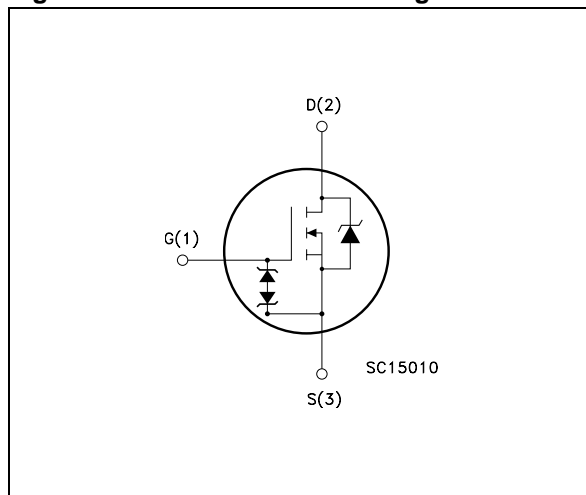


Table 2: Order Codes

PART NUMBER	MARKING	PACKAGE	PACKAGING
STW29NK50ZD	W29NK50ZD	TO-247	TUBE

Table 3: Absolute Maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source Voltage ($V_{GS} = 0$)	500	V
V_{DGR}	Drain-gate Voltage ($R_{GS} = 20\text{ K}\Omega$)	500	V
V_{GS}	Gate- source Voltage	± 30	V
I_D	Drain Current (continuous) at $T_C = 25^\circ\text{C}$	29	A
I_D	Drain Current (continuous) at $T_C = 100^\circ\text{C}$	18.27	A
$I_{DM}^{(*)}$	Drain Current (pulsed)	116	A
P_{TOT}	Total Dissipation at $T_C = 25^\circ\text{C}$	350	W
	Derating Factor	2.77	W/ $^\circ\text{C}$
$V_{ESD(G-S)}$	Gate source ESD (HBM-C = 100pF, R = 1.5 K Ω)	6000	V
dv/dt (1)	Peak Diode Recovery voltage slope	4.5	V/ns
T_{stg} T_j	Storage Temperature Operating Junction Temperature	-55 to 150	$^\circ\text{C}$

(*) Pulse width limited by safe operating area

(1) $I_{SD} \leq 29\text{ A}$, $di/dt \leq 200\text{ A}/\mu\text{s}$, $V_{DD} \leq V_{(BR)DSS}$, $T_j \leq T_{JMAX}$

Table 4: Thermal Data

$R_{thj-case}$	Thermal Resistance Junction-case Max	0.36	$^\circ\text{C}/\text{W}$
$R_{thj-amb}$ T_I	Thermal Resistance Junction-ambient Max Maximum Lead Temperature For Soldering Purpose	50 300	$^\circ\text{C}/\text{W}$ $^\circ\text{C}$

Table 5: Avalanche Characteristics

Symbol	Parameter	Max Value	Unit
I_{AR}	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by T_j max)	29	A
E_{AS}	Single Pulse Avalanche Energy (starting $T_j = 25^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50\text{ V}$)	500	mJ

Table 6: Gate-Source Zener Diode

Symbol	Parameter	Test Condition	Min.	Typ.	Max	Unit
BV_{GSO}	Gate-Source Breakdown Voltage	$I_{gs} = \pm 1\text{ mA}$ (Open Drain)	30			A

PROTECTION FEATURES OF GATE-TO-SOURCE ZENER DIODES

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

TABLE 7: ELECTRICAL CHARACTERISTICS ($T_{CASE} = 25^{\circ}C$ UNLESS OTHERWISE SPECIFIED)**On /Off**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source Breakdown Voltage	$I_D = 1\text{ mA}$, $V_{GS} = 0$	500			S
I_{DSS}	Zero Gate Voltage Drain Current ($V_{GS} = 0$)	$V_{DS} = \text{Max Rating}$ $V_{DS} = \text{Max Rating}$, $T_C = 125^{\circ}C$			1 50	μA μA
I_{GSS}	Gate-body Leakage Current ($V_{DS} = 0$)	$V_{GS} = \pm 20\text{ V}$			± 10	μA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 150\text{ }\mu A$	3	3.75	4.5	V
$R_{DS(on)}$	Static Drain-source On Resistance	$V_{GS} = 10\text{ V}$, $I_D = 14.5\text{ A}$		0.11	0.15	Ω

Table 8: Dynamic

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$g_{fs} (1)$	Forward Transconductance	$V_{DS} = 15\text{ V}$, $I_D = 14.5\text{ A}$		28		S
C_{iss} C_{oss} C_{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25\text{ V}$, $f = 1\text{ MHz}$, $V_{GS} = 0$		6000 570 155		pF pF pF
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	Turn-on Delay Time Rise Time Turn-off-Delay Time Fall Time	$V_{DD} = 400\text{ V}$, $I_D = 14.5\text{ A}$, $R_G = 4.7\text{ }\Omega$, $V_{GS} = 10\text{ V}$ (Resistive Load see Figure 4))		TBD TBD TBD TBD		ns ns ns ns
Q_g Q_{gs} Q_{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 480\text{ V}$, $I_D = 14.5\text{ A}$, $V_{GS} = 10\text{ V}$		180 TBD TBD	200	nC nC nC

Table 9: Source Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
I_{SD} $I_{SDM} (2)$	Source-drain Current Source-drain Current (pulsed)				29 116	A A
$V_{SD} (1)$	Forward On Voltage	$I_{SD} = 29\text{ A}$, $V_{GS} = 0$			1.6	V
t_{rr} Q_{rr} I_{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 29\text{ A}$, $di/dt = 100\text{ A}/\mu s$ $V_{DD} = 30\text{ V}$, $T_j = 25^{\circ}C$ (see test circuit Figure 5)		TBD TBD TBD		ns μC A
t_{rr} Q_{rr} I_{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 29\text{ A}$, $di/dt = 100\text{ A}/\mu s$ $V_{DD} = 30\text{ V}$, $T_j = 150^{\circ}C$ (see test circuit Figure 5)		TBD TBD TBD		ns μC A

(1) Pulsed: Pulse duration = 300 μs , duty cycle 1.5 %.

(2) Pulse width limited by safe operating area.

Figure 3: Unclamped Inductive Load Test Circuit

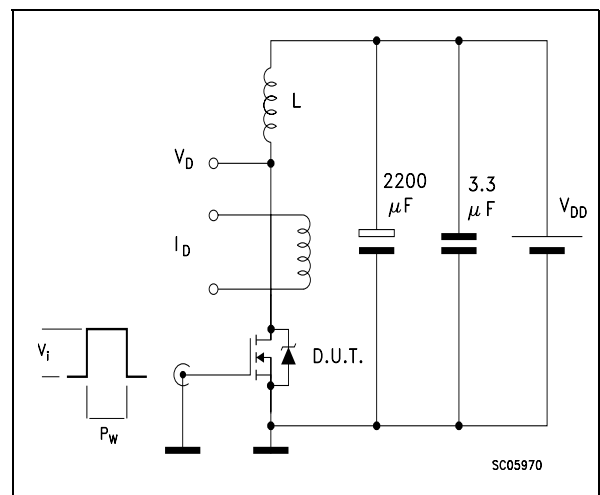


Figure 4: Switching Times Test Circuit For Resistive Load

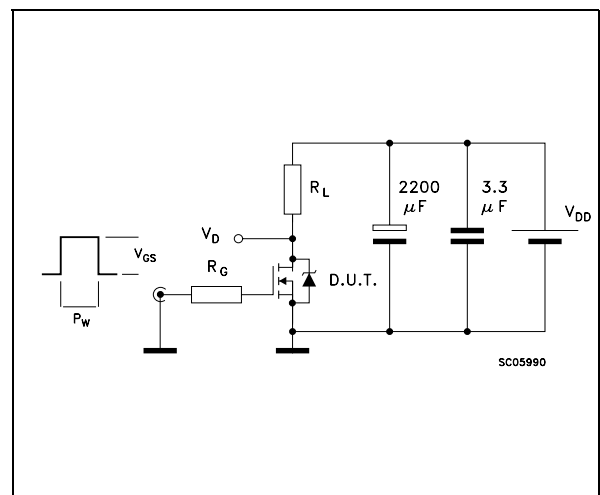


Figure 5: Test Circuit For Inductive Load Switching and Diode Recovery Times

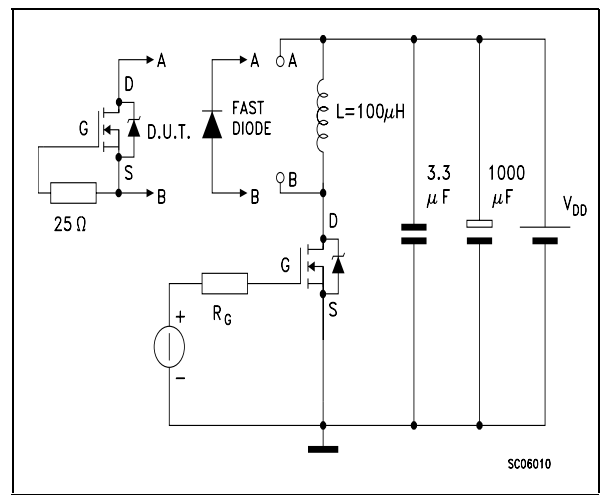


Figure 6: Unclamped Inductive Wavform

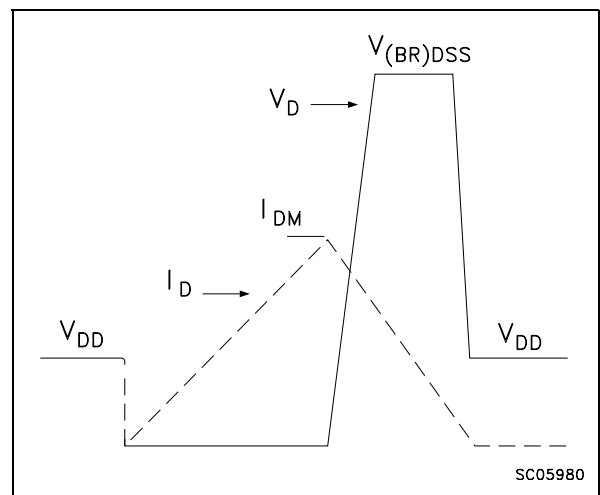
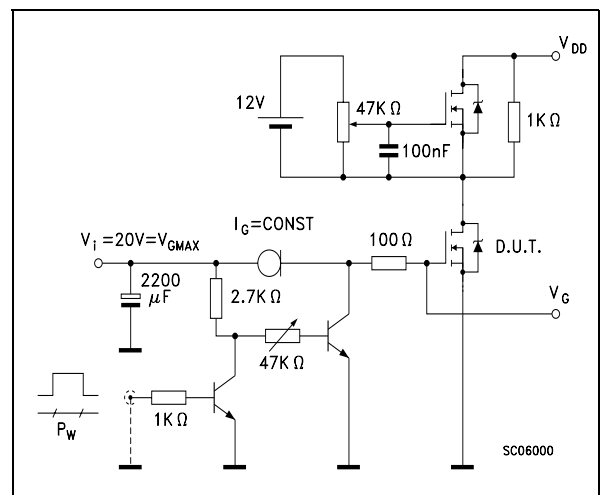
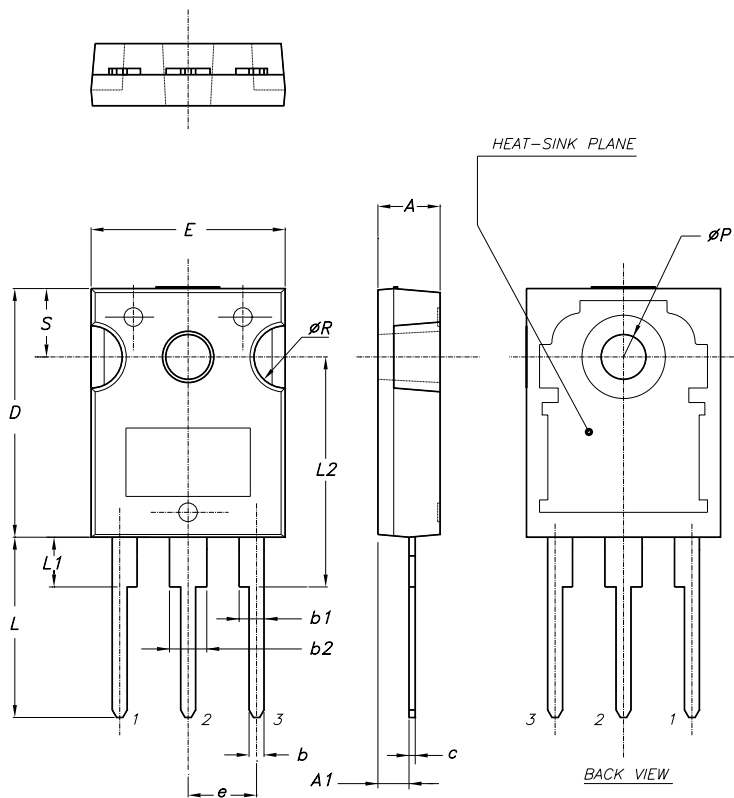


Figure 7: Gate Charge Test Circuit



TO-247 MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A	4.85		5.15	0.19		0.20
A1	2.20		2.60	0.086		0.102
b	1.0		1.40	0.039		0.055
b1	2.0		2.40	0.079		0.094
b2	3.0		3.40	0.118		0.134
c	0.40		0.80	0.015		0.03
D	19.85		20.15	0.781		0.793
E	15.45		15.75	0.608		0.620
e		5.45			0.214	
L	14.20		14.80	0.560		0.582
L1	3.70		4.30	0.14		0.17
L2		18.50			0.728	
øP	3.55		3.65	0.140		0.143
øR	4.50		5.50	0.177		0.216
S		5.50			0.216	



Rev.E

Table 10: Revision History

Date	Revision	Description of Changes
05-Feb-2004	1	First Release.
06-Dec-2004	2	Some electrical value changed

Information furnished is believed to be accurate and reliable. However, STMicroelectronics assumes no responsibility for the consequences of use of such information nor for any infringement of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of STMicroelectronics. Specifications mentioned in this publication are subject to change without notice. This publication supersedes and replaces all information previously supplied. STMicroelectronics products are not authorized for use as critical components in life support devices or systems without express written approval of STMicroelectronics.

The ST logo is a registered trademark of STMicroelectronics

All other names are the property of their respective owners

© 2004 STMicroelectronics - All Rights Reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com